

2016 87th ARFTG Microwave Measurement Conference (ARFTG 2016)

**San Francisco, California, USA
27 May 2016**



**IEEE Catalog Number: CFP16ARF-POD
ISBN: 978-1-5090-1309-8**

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IEEE Catalog Number:	CFP16ARF-POD
ISBN (Print-On-Demand):	978-1-5090-1309-8
ISBN (Online):	978-1-5090-1308-1

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